



ISC Audits & Reviews SC Summary (Oct 18, 2019)

Doc.	Title	Result
6351E	New Standard: Specification for Viewing Angle of Flat Panel Displays	Failed
6525	Reapproval of SEMI E166-0814: Specification for 450 mm Cluster Module Interface: Mechanical Interface and Transport Standard	Passed
R6295	Ratification Ballot - New Standard: Test Method for Extension of Flexible Thin Film PV Modules	Passed
R6472	Ratification Ballot - New Standard: Test Method for Measuring Surface Metal Contamination Through ICP-MS of Critical Chamber Components Used in Semiconductor Wafer Processing	Passed
R6519	Ratification Ballot - Revision of SEMI M53-0219 - Practice for Calibrating Scanning Surface Inspection Systems Using Certified Depositions of Monodisperse Reference Spheres on Unpatterned Semiconductor Wafer Surfaces	Passed

Line Item (LI)

For more information, please contact the SEMI Standards Engineer/Coordinator.
(<http://www.semi.org/standards/contacts>) nearest you.

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Oct 18, 2019